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Fairchild Semiconductor FDB3860

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Datasheet of FDB3860 - MOSFET N-CH 100V 6.4A D2PAK

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March 2009

FDB3860

N-Channel PowerTrench® MOSFET **100 V, 30 A, 37 m**Ω

Features

- Max $r_{DS(on)} = 37 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 5.9 \text{ A}$
- High performance trench technology for extremely low r_{DS(on)}
- 100% UIL tested
- RoHS Compliant

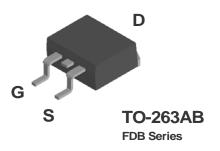


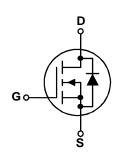
General Description

This N-Channel MOSFET is rugged gate version of Fairchild Semiconductor's advanced Power Trench® process. This part is tailored for low $r_{DS(on)}$ and low Qg figure of merit, with avalanche ruggedness for a wide range of switching applications.

Applications

- DC-AC Conversion
- Synchronous Rectifier





MOSFET Maximum Ratings $T_C = 25$ °C unless otherwise noted

Symbol	Parameter			Ratings	Units	
V_{DS}	Drain to Source Voltage			100	V	
V _{GS}	Gate to Source Voltage			±20	V	
	Drain Current -Continuous (Silicon limited)	T _C = 25 °C		30		
I_D	-Continuous	T _A = 25 °C	(Note 1a)	6.4	Α	
	-Pulsed			60		
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	96	mJ	
В	Power Dissipation	T _C = 25 °C		71	W	
P_{D}	Power Dissipation	T _A = 25 °C	(Note 1a)	3.1	VV	
T _J , T _{STG}	Operating and Storage Junction Temperature F	Range		-55 to +150	°C	

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.75	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a	40	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDB3860	FDB3860	TO-263AB	330 mm	24 mm	800 units



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Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	acteristics					
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		104		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			1	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$		±100	nA	

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	3.8	4.5	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		-11		mV/°C
Static Drain to Source On Resistance		$V_{GS} = 10 \text{ V}, I_D = 5.9 \text{ A}$		31	37	mΩ
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 5.9 \text{ A}, T_J = 125 ^{\circ}\text{C}$		56	67	11122
9 _{FS}	Forward Transconductance	$V_{DS} = 10 \text{ V}, I_{D} = 5.9 \text{ A}$		18		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50 V V 0 V	1310	1740	pF
Coss	Output Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$	100	130	рF
C _{rss}	Reverse Transfer Capacitance	1 = 1 101112	40	65	pF
R_{α}	Gate Resistance		1.7		Ω

Switching Characteristics

t _{d(on)}	Turn-On Delay Time		12	22	ns
t _r	Rise Time	$V_{DD} = 50 \text{ V}, I_{D} = 5.9 \text{ A},$	6	12	ns
t _{d(off)}	Turn-Off Delay Time	$V_{DD} = 50 \text{ V}, I_{D} = 5.9 \text{ A},$ $V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$	17	31	ns
t _f	Fall Time		3	10	ns
Q_g	Total Gate Charge at 10 V		21	30	nC
Q _{gs}	Gate to Source Charge	$V_{DD} = 50 \text{ V}, I_{D} = 5.9 \text{ A}$	6.9		nC
Q _{gd}	Gate to Drain "Miller" Charge		5.4		nC

Drain-Source Diode Characteristics

V.	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = 2.0 \text{ A}$ (Note 2)	0.7	1.2	V
V _{SD} Sc	Source to Drain blode 1 of ward voltage	$V_{GS} = 0 \text{ V}, I_S = 5.9 \text{ A}$ (Note 2)	0.8	1.3	V
t _{rr}	Reverse Recovery Time	I _E = 5.9 A, di/dt = 100 A/μs	35	56	ns
Qrr	Reverse Recovery Charge	$I_{\rm F} = 5.9 \text{A}, \text{di/dt} = 100 \text{A/} \mu \text{S}$	37	60	nC

Notes:

¹³ R_{BJA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{BJC} is guaranteed by design while R_{BJA} is determined by the user's board design.

a. 40 °C/W when mounted on a 1 in² pad of 2 oz copper

b. 62.5 °C/W when mounted on a minimum pad.

^{2:} Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%. 3: Starting T $_J$ = 25 °C, L = 3 mH, I $_{AS}$ = 8 A, V $_{DD}$ = 100 V, V $_{GS}$ = 10 V.



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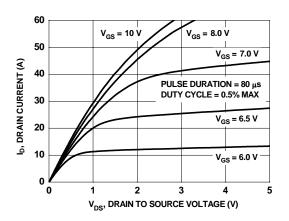


Figure 1. On Region Characteristics

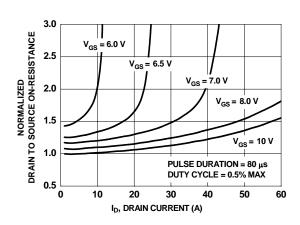


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

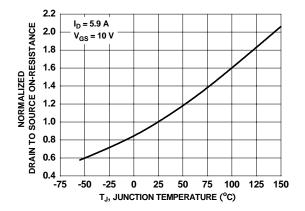


Figure 3. Normalized On Resistance vs Junction Temperature

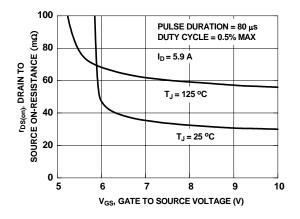


Figure 4. On-Resistance vs Gate to Source Voltage

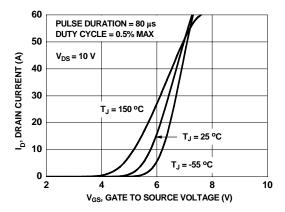


Figure 5. Transfer Characteristics

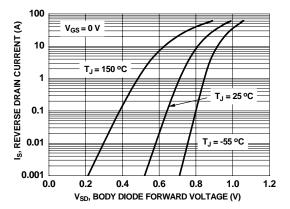


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

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Typical Characteristics T_J = 25 °C unless otherwise noted

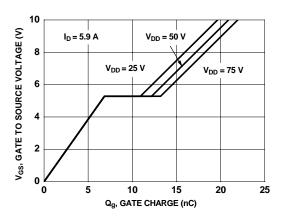


Figure 7. Gate Charge Characteristics

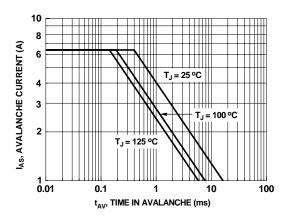


Figure 9. Unclamped Inductive Switching Capability

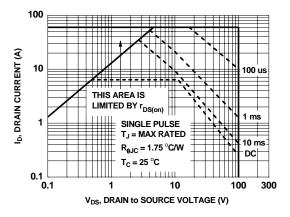


Figure 11. Forward Bias Safe Operating Area

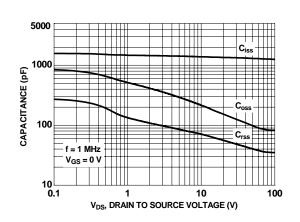


Figure 8. Capacitance vs Drain to Source Voltage

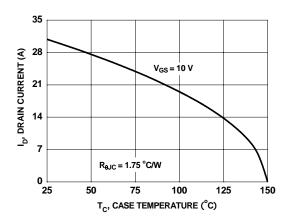


Figure 10. Maximum Continuous Drain Current vs Case Temperature

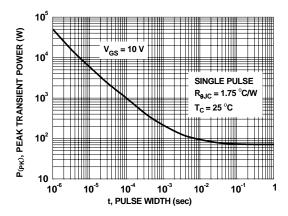


Figure 12. Single Pulse Maximum Power Dissipation

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Typical Characteristics T_J = 25 °C unless otherwise noted

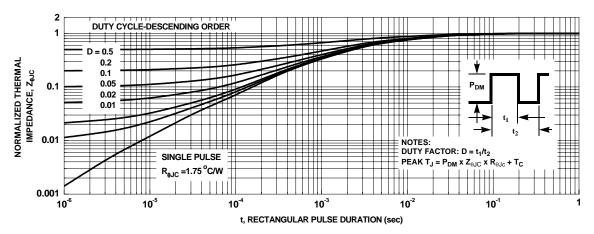


Figure 13. Junction-to-Case Transient Thermal Response Curve

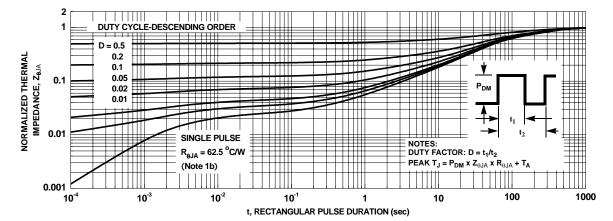


Figure 14. Junction-to-Ambient Transient Thermal Response Curve

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Preliminary Datasheet



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